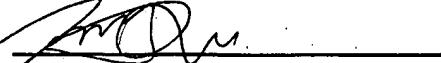
**SECTION 2. FORMS PTO/SB/08A and 08B (formerly Form PTO-1449)****IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Lang, P. Attorney Docket: 3155/102
Serial No: 09/942,528 Art Group Unit: 2624
Date Filed: August 29, 2001 Examiner Name: Lu, Tom Y.
Invention: Methods and Devices for Quantitative Analysis of X-ray Images

**LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Reference Number	Country Code	Document Number	Publication Date	Patentee or Applicant	Class/Subclass
TYL	AA	WO	00/33157	06/08/2000	Hologic, Inc.	G06F

OTHER DOCUMENTS		
Examiner Initials	Reference Number	Title of Article, Title of Journal, Volume Number, Page Numbers, Date
TYL	AB	<i>Patent Abstracts in Japan</i> , April 23, 1993, 1 Page – JP 05099829 (Matsushita Electric Ind. Co., Ltd., October 4, 1991)
TYL	AC	<i>Patent Abstracts in Japan</i> , July 16, 1996, 1 Page – JP 08186762 (Toshiba Medical Eng. Co. Ltd., December 12, 1994)
TYL	AD	<i>Patent Abstracts in Japan</i> , May 29, 1998, 1 Page – JP 10145396 (Siemens AG, June 26, 1997)
TYL	AE	<i>Patent Abstracts in Japan</i> , March 9, 1999, 1 Page – JP 11069136 (Canon Inc., August 18, 1997)
TYL	AF	<i>Patent Abstracts in Japan</i> , April 23, 1999, 1 Page – JP 11112877 (Fuji Photo Film Co., Ltd., September 30, 1997)
TYL	AG	<i>Patent Abstracts in Japan</i> , May 9, 2000, 1 Page – JP 2000126168 (Teijin Ltd., October 22, 1998)
TYL	AH	<i>Patent Abstracts in Japan</i> , May 23, 2000, 1 Page – JP 2000139889 (Canon, Inc., August 24, 1999)

Examiner Signature: 

Date Considered: 2/12/07

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.